

August 2009

### FDMS6673BZ

# P-Channel PowerTrench<sup>®</sup> MOSFET -30 V, -28 A, 6.8 m $\Omega$

### **Features**

- Max  $r_{DS(on)}$  = 6.8 m $\Omega$  at  $V_{GS}$  = -10 V,  $I_D$  = -15.2 A
- Max  $r_{DS(on)}$  = 12.5 m $\Omega$  at  $V_{GS}$  = -4.5 V,  $I_D$  = -11.2 A
- Advanced Package and Silicon combination for low r<sub>DS(on)</sub>
- HBM ESD protection level of 8 kV typical(note 3)
- MSL1 robust package design
- RoHS Compliant

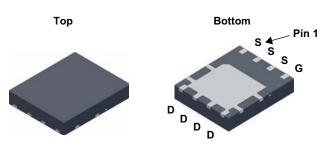


### **General Description**

The FDMS6673BZ has been designed to minimize losses in load switch applications. Advancements in both silicon and package technologies have been combined to offer the lowest  $r_{\text{DS}(\text{on})}$  and ESD protection.

### **Applications**

- Load Switch in Notebook and Server
- Notebook Battery Pack Power Management



Power 56

# D 5 4 G D 6 3 S D 7 2 S D 8 1 S

### **MOSFET Maximum Ratings** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			-30	V
$V_{GS}$	Gate to Source Voltage			±25	V
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25 °C		-28	
	-Continuous (Silicon limited)	T <sub>C</sub> = 25 °C		-90	
ID	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	-15.2	- A
	-Pulsed			-120	
Б	Power Dissipation	T <sub>C</sub> = 25 °C		73	w
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.5	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C	

### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.7	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	C/VV

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS6673BZ	FDMS6673BZ	Power 56 13 " 12		12 mm	3000 units

# **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = -250 μA, V <sub>GS</sub> = 0 V	-30			V
$\frac{\Delta BV_{DS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, referenced to 25 °C		-18		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -24 V, V <sub>GS</sub> = 0 V			-1	μА
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±25 V, V <sub>DS</sub> = 0 V			±10	μА

### On Characteristics

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-1.0	-1.8	-3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25 °C		7		mV/°C
		V <sub>GS</sub> = -10 V, I <sub>D</sub> = -15.2 A		5.2	6.8	
r <sub>DS(on)</sub>	r <sub>DS(on)</sub> Static Drain to Source On Resistance	V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -11.2 A		7.8	12.5	mΩ
	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -15.2 A, T <sub>J</sub> = 125 °C		7.5	9.8		
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -15.2 \text{ A}$		76		S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V - 45 V V - 0 V	4444	5915	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = -15 V, V <sub>GS</sub> = 0 V, f = 1 MHz	781	1040	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12	695	1045	pF
$R_g$	Gate Resistance		4.5		Ω

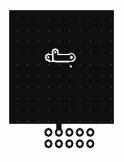
### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time				14	26	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = -15 V, I <sub>D</sub> = -15	$V_{DD}$ = -15 V, $I_{D}$ = -15.2 A, $V_{GS}$ = -10 V, $R_{GEN}$ = 6 $\Omega$		28	45	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = -10 V, R <sub>GEN</sub> =			97	156	ns
t <sub>f</sub>	Fall Time				79	127	ns
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to -10 V			93	130	nC
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to -5 V	$V_{DD} = -15 \text{ V},$		52	73	nC
Q <sub>gs</sub>	Gate to Source Charge		I <sub>D</sub> = -15.2 A		13		nC
$Q_{gd}$	Gate to Drain "Miller" Charge				26		nC

### **Drain-Source Diode Characteristics**

V Source to Drain Diade Ferward V	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -2.1 \text{ A}$ (Note 2)		0.7	1.20	\/
V <sub>SD</sub>	Source to Drain Diode Forward voltage	$V_{GS} = 0 \text{ V}, I_S = -15.2 \text{ A}$ (Note 2)		0.8	1.25	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = -15.2 A, di/dt = 100 A/μs		33	53	ns
Q <sub>rr</sub>	Reverse Recovery Charge			20	32	nC

The R<sub>θ,JA</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>θ,JC</sub> is guaranteed by design while R<sub>θCA</sub> is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

- 2: Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- 3: The diode connected between the gate and source servers only as protection against ESD. No gate overvoltage rating is implied.

### Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

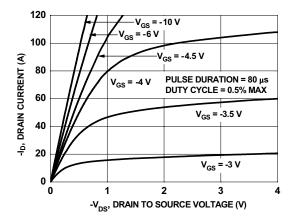


Figure 1. On Region Characteristics

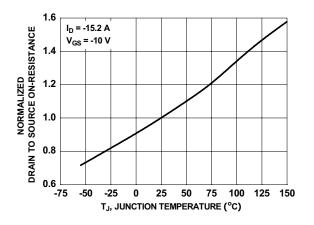


Figure 3. Normalized On Resistance vs Junction Temperature

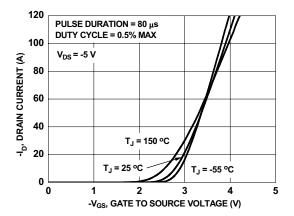


Figure 5. Transfer Characteristics

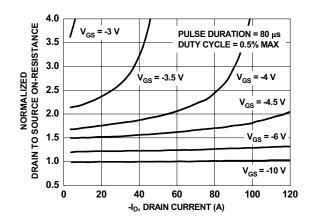


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

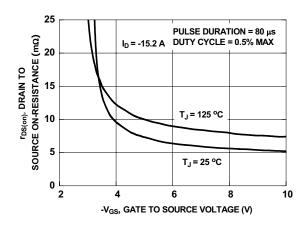


Figure 4. On-Resistance vs Gate to Source Voltage

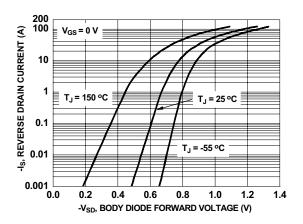


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

### **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

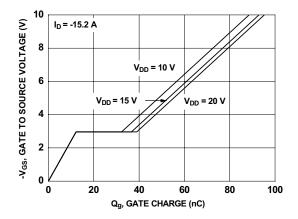


Figure 7. Gate Charge Characteristics

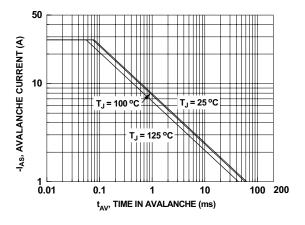


Figure 9. Unclamped Inductive Switching Capability

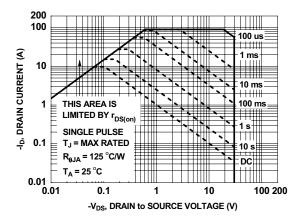


Figure 11. Forward Bias Safe Operating Area

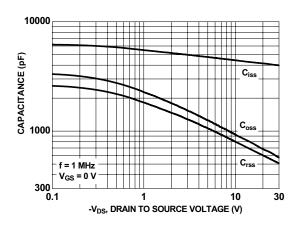


Figure 8. Capacitance vs Drain to Source Voltage

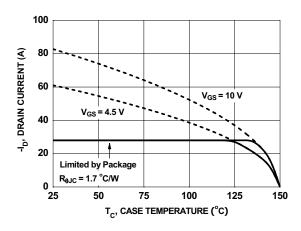


Figure 10. Maximum Continuous Drain Current vs Case Temperature

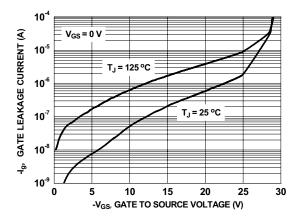


Figure 12. Igss vs Vgss

### **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

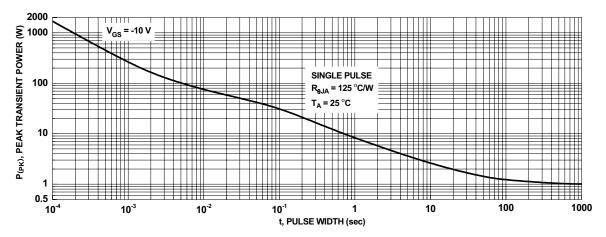


Figure 13. Single Pulse Maximum Power Dissipation

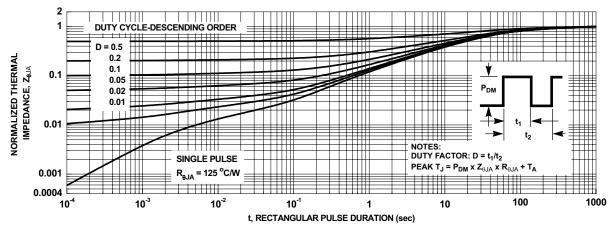
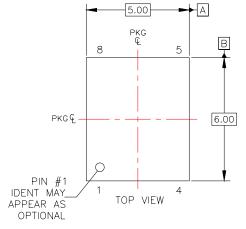
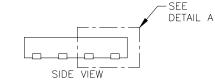
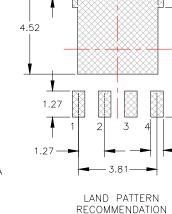


Figure 14. Junction-to-Ambient Transient Thermal Response Curve

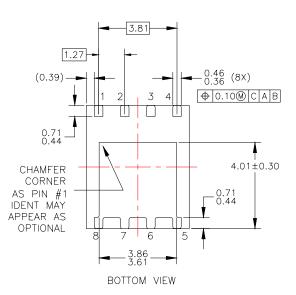
### **Dimensional Outline and Pad Layout**

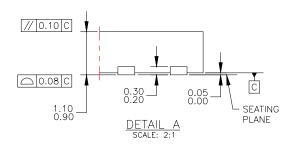


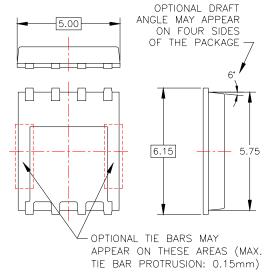




0.77







6.61

0.61

NOTES: UNLESS OTHERWISE SPECIFIED

- A) PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. AA, DATED OCTOBER 2002.
- DATED OCTOBER 2002.

  B) ALL DIMENSIONS ARE IN MILLIMETERS.
  C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- E) DRAWING FILE NAME: PQFN08AREV4





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